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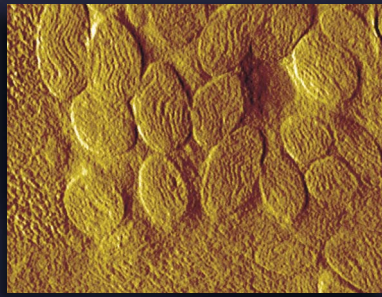
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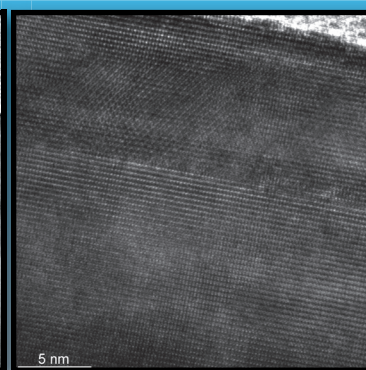
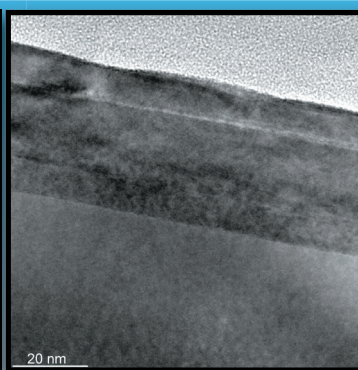
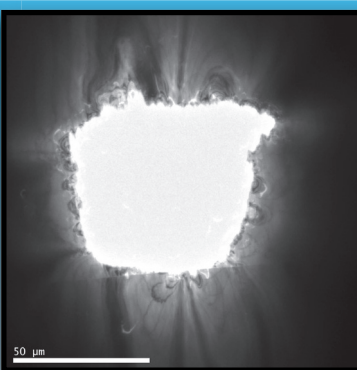
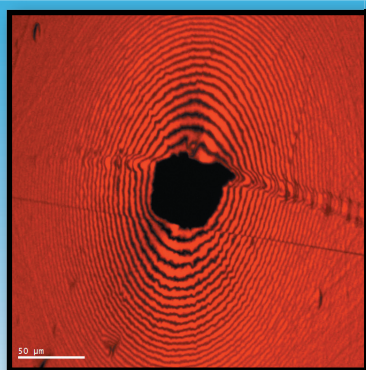
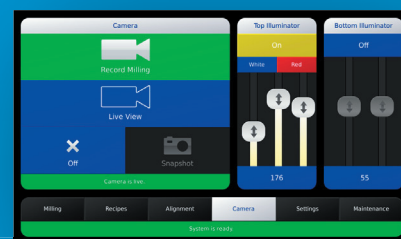
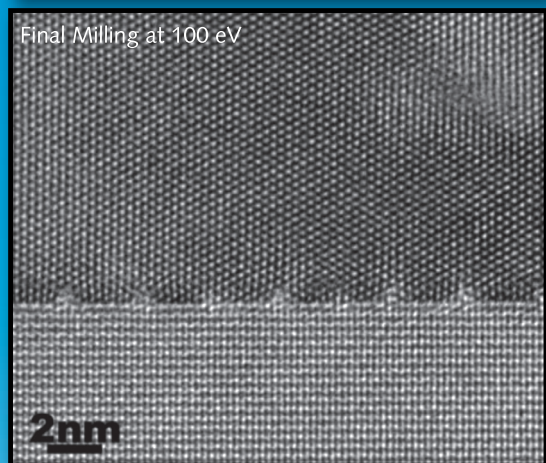
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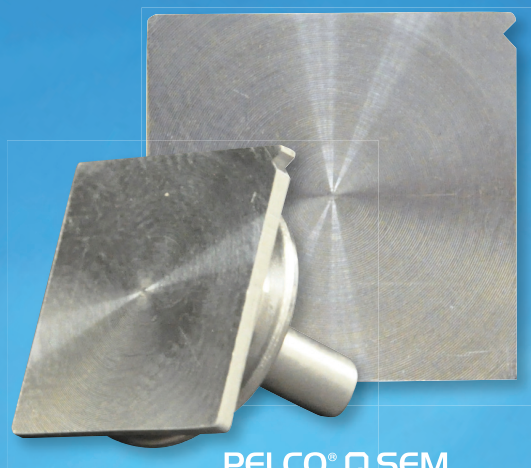
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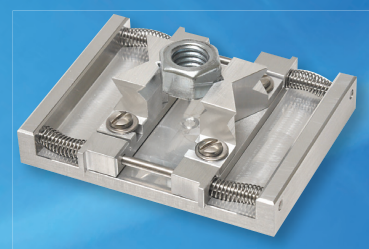
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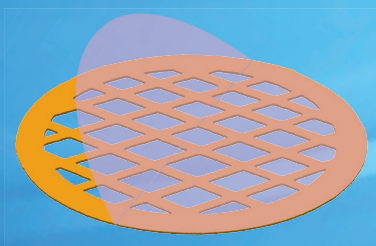
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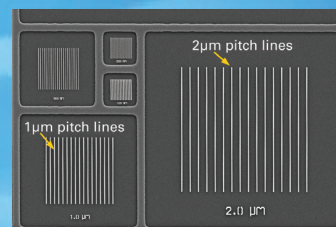
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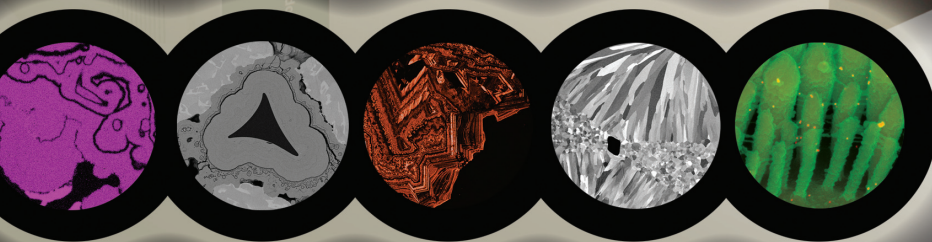
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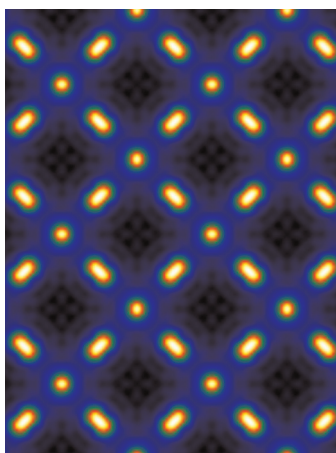
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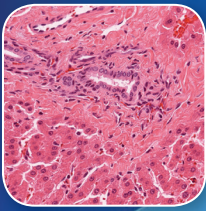
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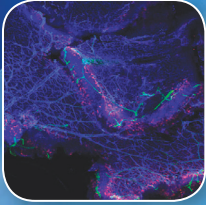
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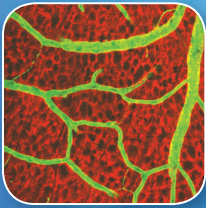


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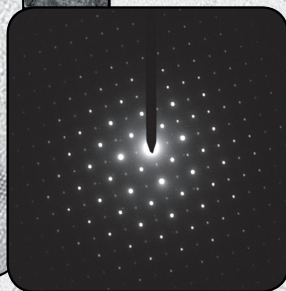
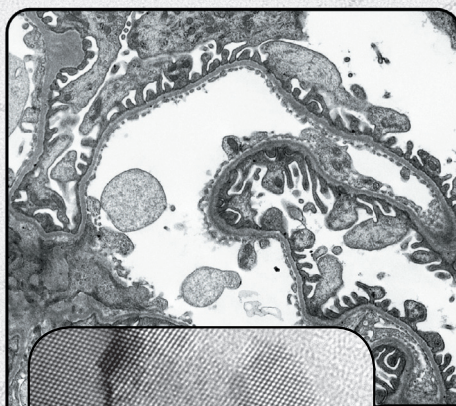


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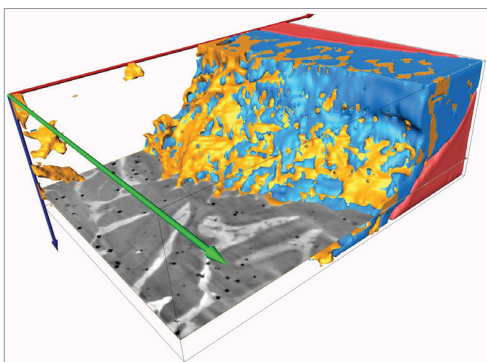
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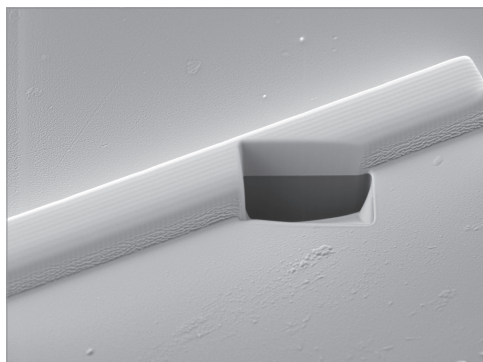
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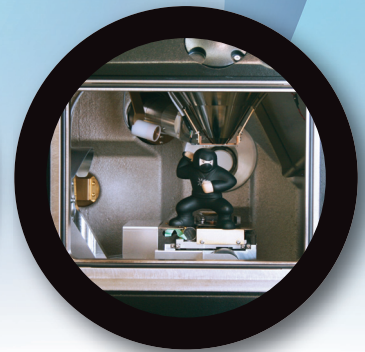
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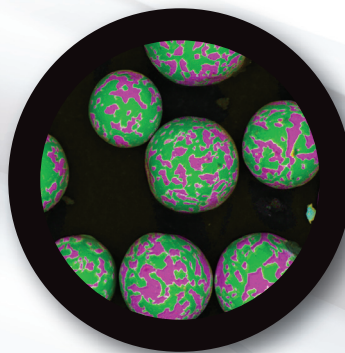
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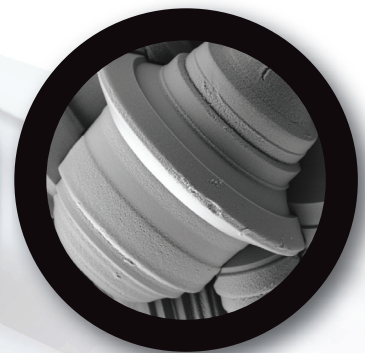
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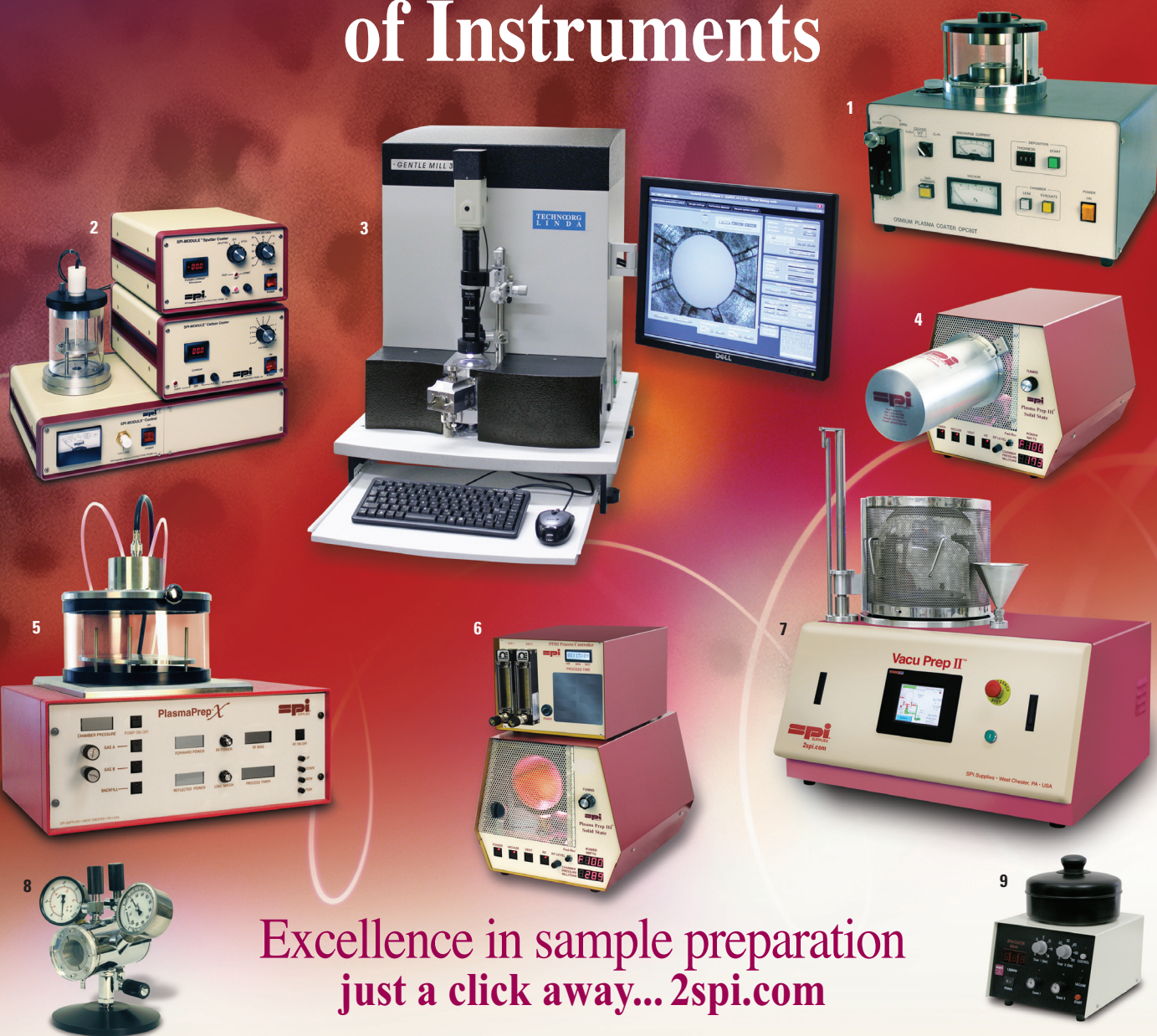


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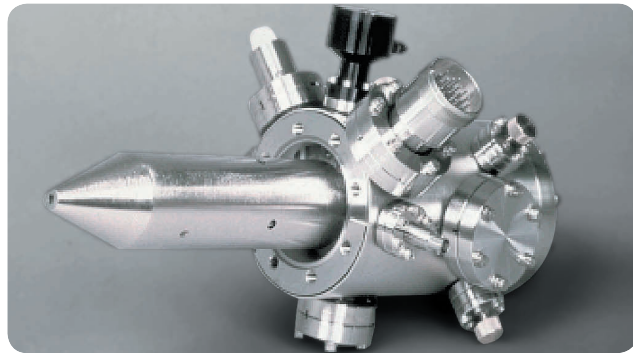
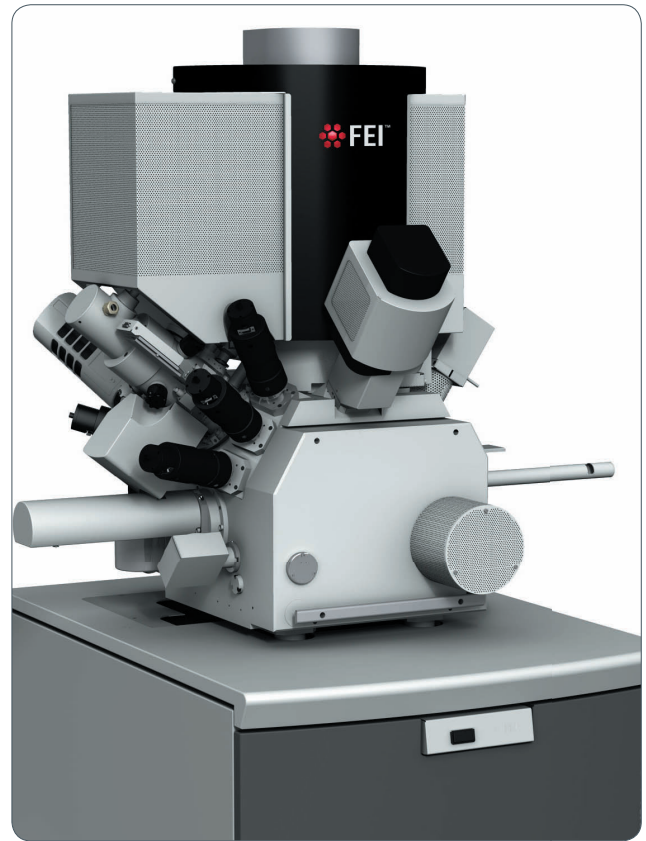
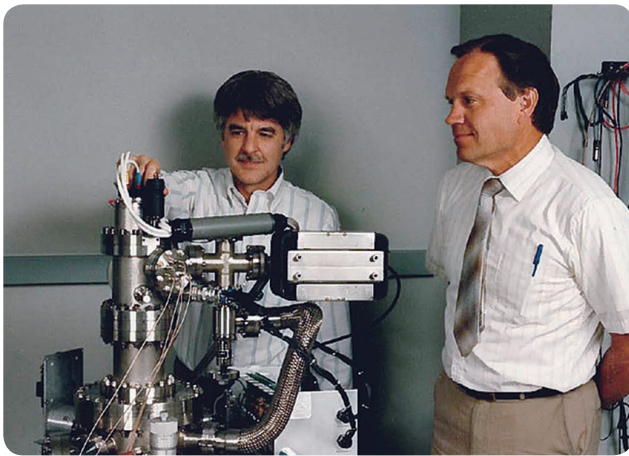
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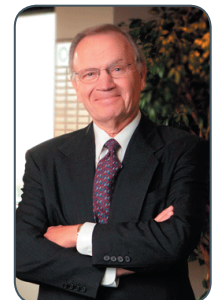




(Top left) Dave Tuggle and FEI founder Lyn Swanson working on an early edition FIB column. **(Bottom left)** A two-lens Schottky column. **(Right)** Helios NanoLab 660.

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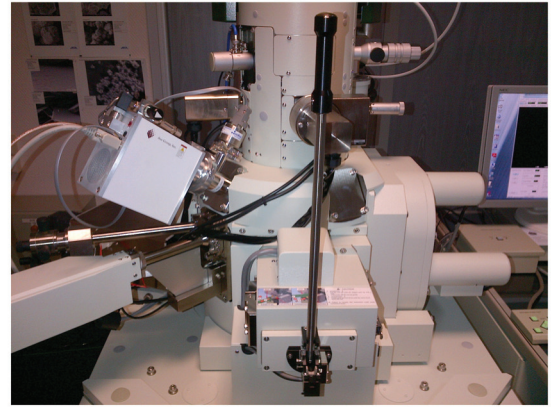




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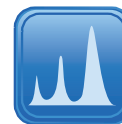
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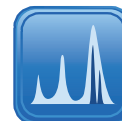
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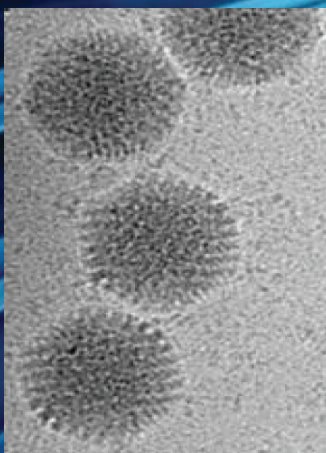
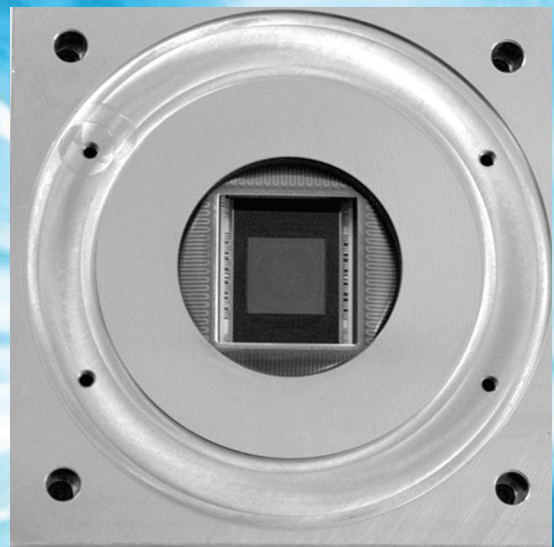
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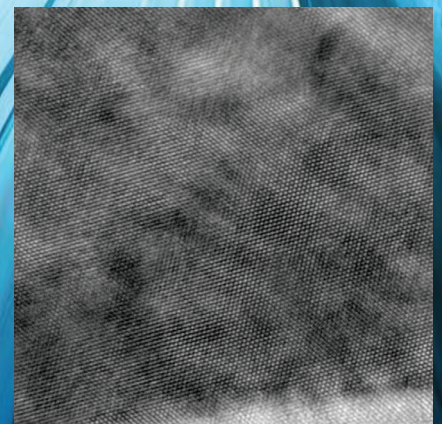


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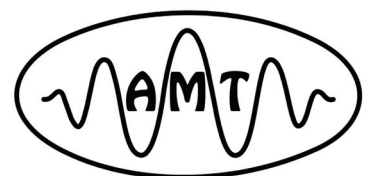
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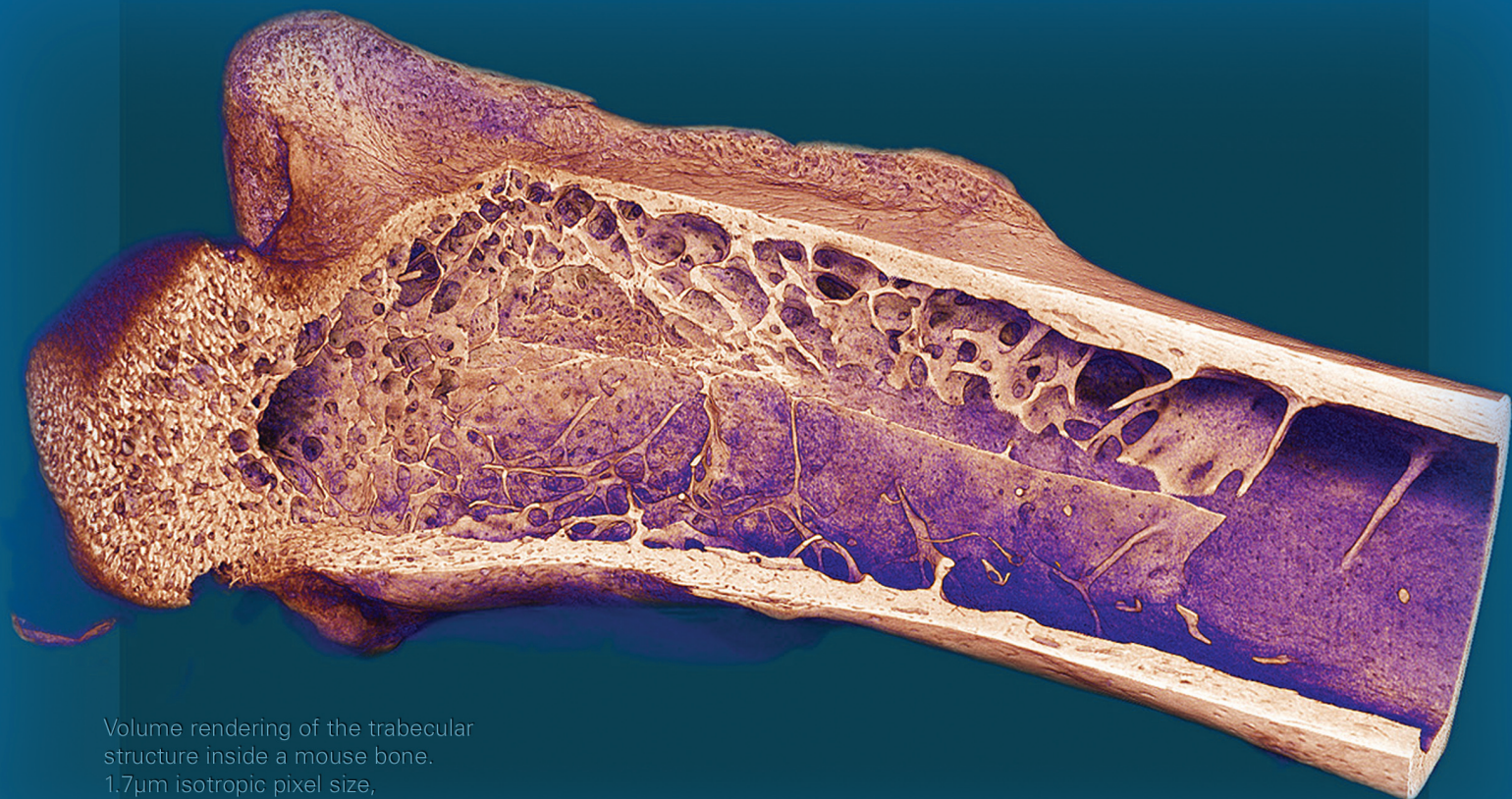


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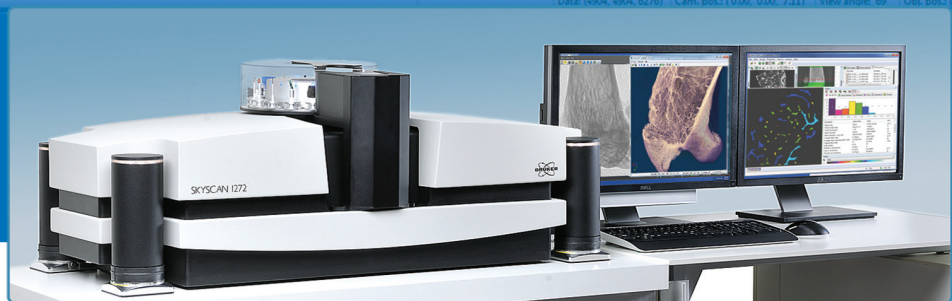




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